



LIST OF REFERENCES CITED BY APPLICANT

Atty Docket No. 4925-112
Serial No.: 09/916,001
Applicant: Miikka HUOMO et al.

Filing Date: July 26, 2001
Group Art:

U.S. PATENT DOCUMENTS

*Ex. Intls.		Document No.	Date	Name	Class	Subclass	Filing Date
	AA						
	AB						
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FOREIGN PATENT DOCUMENTS

*Ex. Intls.		Document No.	Date	Country	Name	Class	Subclas s	Translation Yes/No
<i>EP</i>	AF	07217213	03/07/97	Japan	Toda	H04M	3/5	Yes
	AG							
	AH							
	AI							
	AJ							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AK		
	AL		
	AM		

EXAMINER: **ELISEO RAMOS-FELICIANO**
PATENT EXAMINER *EP*

DATE CONSIDERED: 4-30-04

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Atty Docket No.: 4925-112

Filing Date: July 26, 2001

Serial No.: 09/916,001

Group Art: 2681

Applicant: Miikka HUOMO et al.

U.S. PATENT DOCUMENTS

*Ex. Intls.		Document No.	Date	Name	Class	Subclass	Filing Date
	AA	6,192,245	02/2001	Jones et al.	455	437	07/1995
	AB	6,044,249	03/2000	Chandra et al.	455	62	11/1996
	AC	6,445,917	09/2002	Bark et al.	455	423	05/1999
	AD						
	AE						

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	AF							
	AG							
	AH							
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